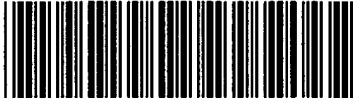


<i>Search Notes</i> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/801,872	MEEK ET AL.	
	Examiner	Art Unit	
	Quynh H. Nguyen	2614	

